

Investigation of Interactions Between Co-fired LTCC Components

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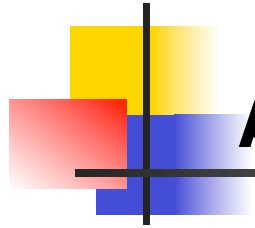
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PURPOSE OF THE PRESENTATION

- To present the results of thick-film resistor (TFR) properties measured in co-fired LTCC (**L**ow **T**emperature **C**o-fired **C**eramic) structures
- To determine the effects of paste properties and processing conditions on properties
- To interpret the results using characterization tools such as SEM, EDXS analysis, dilatometry



AN OVERVIEW

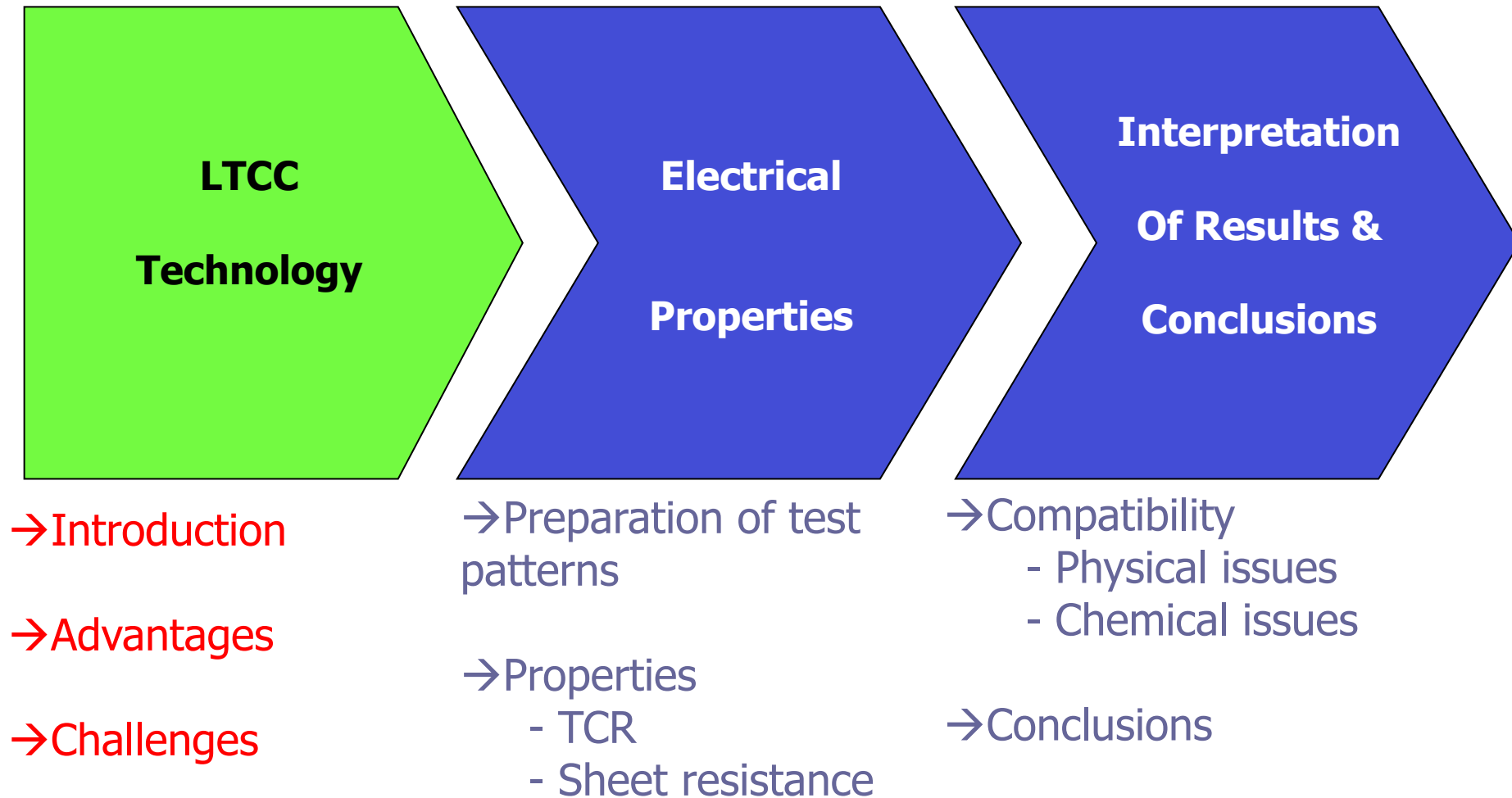
- Integration of thick-film pastes into LTCC sheets increases reliability concerns
- Reliability depends strongly on the **physical and chemical compatibility** of different components fired together
- The challenges at this critical point has to be well-understood and controlled

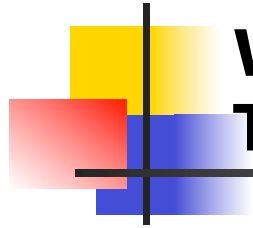


APPLICATION EXAMPLES



OUTLINE OF THIS PRESENTATION





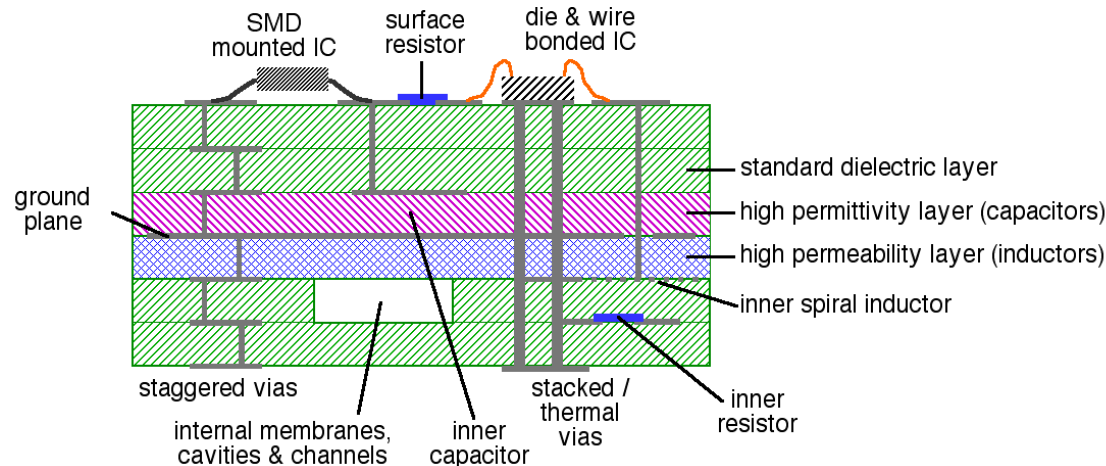
WHAT IS LTCC TECHNOLOGY?

Based on LTCC tapes of various thicknesses which

- sinter below 900°C
- are glass ceramics with excellent dielectric properties
- are screen-printed and co/post-fired with thick-film electronic passive components

| | COMPONENTS | | |
|------------------|--|--|---|
| | SUBSTRATE | PASSIVES | |
| Components | Tape | Conductor | Resistor |
| Function | Dielectric layer | Thick-film paste | Thick-film paste |
| Functional group | Dielectric powder | Precious metal, fine size powder | Conductive oxide, fine size powder |
| Glass | <ul style="list-style-type: none"> ✗ Lowers T_{firing} ✗ increases dielectric strength and density | <ul style="list-style-type: none"> ✗ Lowers T_{firing} ✗ increases adhesion to substrate and density | <ul style="list-style-type: none"> ✗ Lowers T_{firing} ✗ increases density ✗ surrounds conductive powder |
| Organics | Binder, solvent, dispersant for appropriate rheology | | |

ADVANTAGES OF LTCC TECHNOLOGY AT A GLANCE

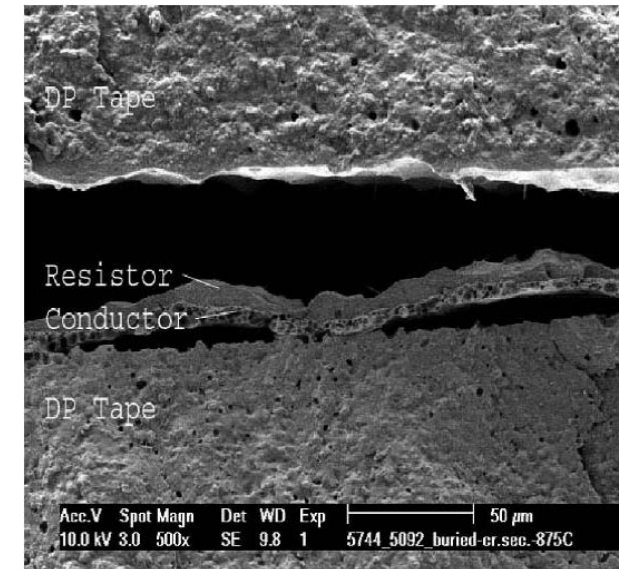
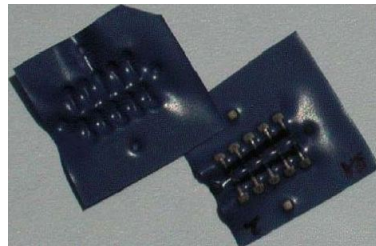
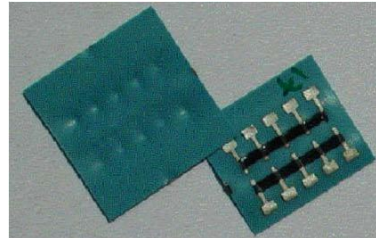


- ➔ Excellent dielectric properties for high frequencies
- ➔ **Ease of machinability of tapes**
- ➔ Cost effective
- ➔ **High density packaging**
- ➔ Excellent chemical / thermal stability
- ➔ Hermeticity of the structures
- ➔ Mechanical and electrical functions in one system

CHALLENGES

1. Physical Issues

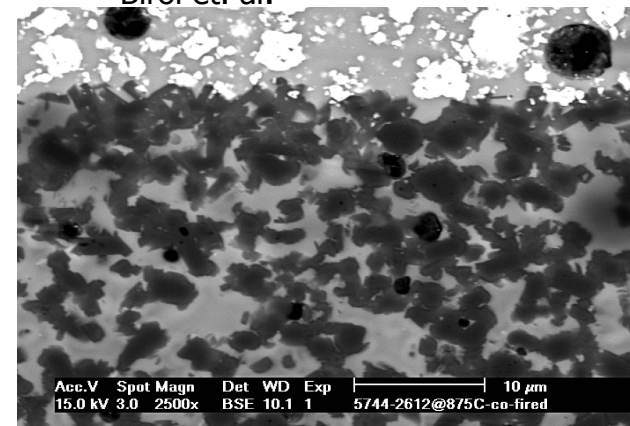
- differential shrinkage
- degassing
- lamination



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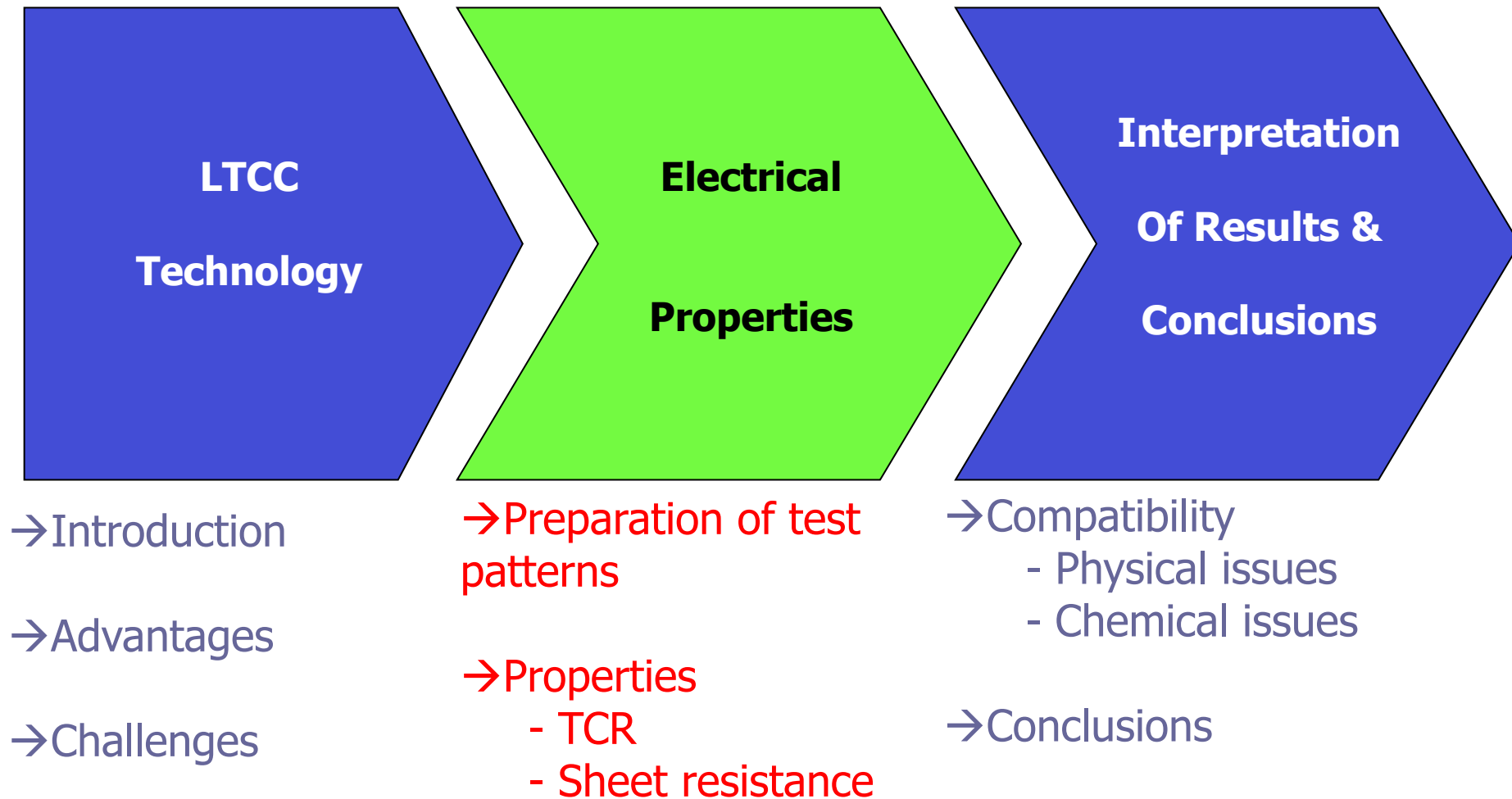
2. Chemical Issues

- Interaction of components
- Oxidizing /reducing conditions



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OUTLINE OF THIS PRESENTATION



PREPARATION OF TEST PATTERNS

| Function | Commercial Product | Chemical Origin | Specification |
|------------------|------------------------------|-----------------|---|
| Substrate | DuPont (DP) 951-AX LTCC Tape | Glass-ceramic | 254 μ -thickness |
| Conductor | ESL 8837 | Au | Organo-metallic |
| | DP 5744 | Au | Classic |
| Resistor | DP 5092 D | Ru-based | $R_s = 100\Omega / \square$ at 25°C TCR = 2400 ppm/K |

| Firing method | Screen-printing | Drying | Lamination | Firing (heating cycle) |
|---------------|-----------------|--------|------------|------------------------|
| Co-fired | + | + | | + |
| Buried | + | + | + | + |

Heating Cycle

STEP1: 25°C \rightarrow 440°C
5°C/min, $t_{\text{dwell}} = 120\text{min}$

STEP2: 440°C $\rightarrow T_{\text{firing}}$
5°C/min, $t_{\text{dwell}} = 25\text{min}$

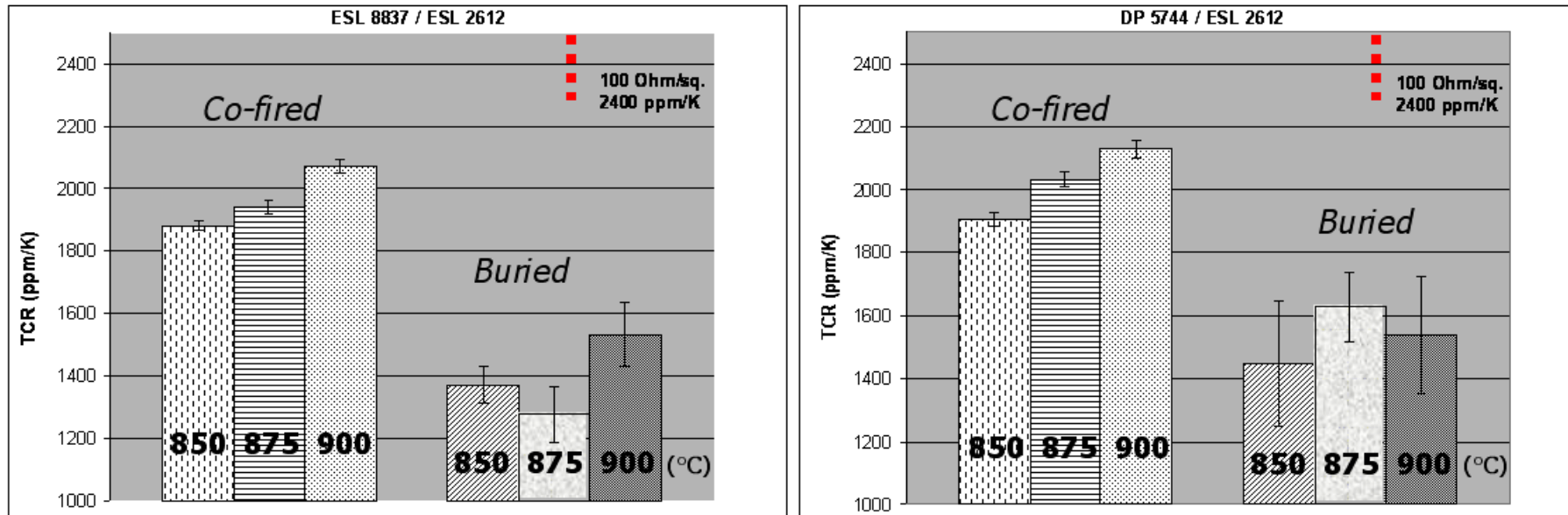
STEP3: $T_{\text{firing}} \rightarrow 25^\circ\text{C}$
10°C/min

➡ Au-based conductors selected

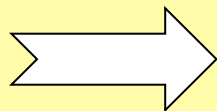
(they are observed to result in **less deformation** on tapes compared to other compositions such as Ag/Pd, Ag/Pd/Pt, Pt)

PROPERTIES

TEMPERATURE COEFFICIENT OF RESISTANCE (TCR)



Co-fired
Samples

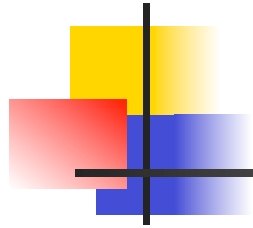


- fall in a TCR range close to producer-specified values
- standard deviation is very small

Buried
Samples

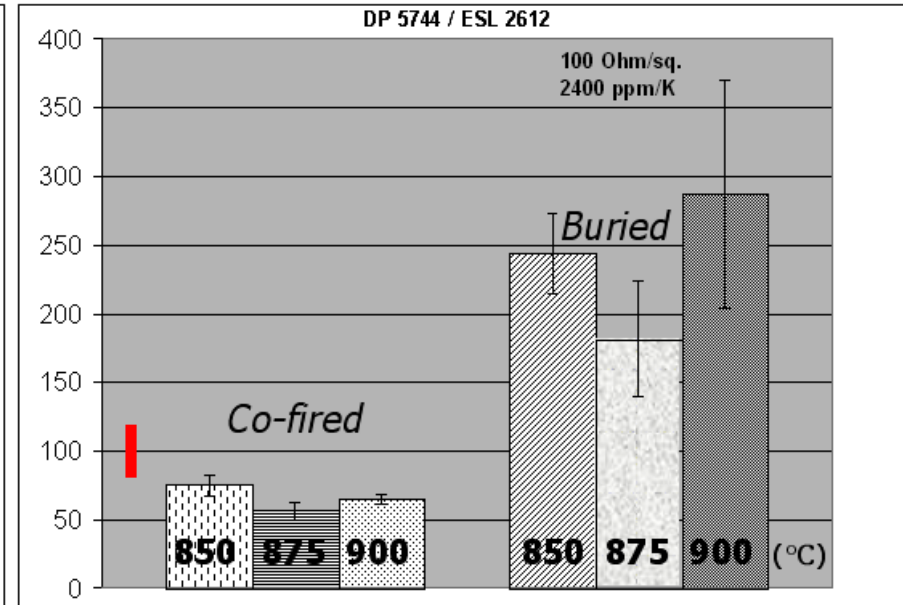
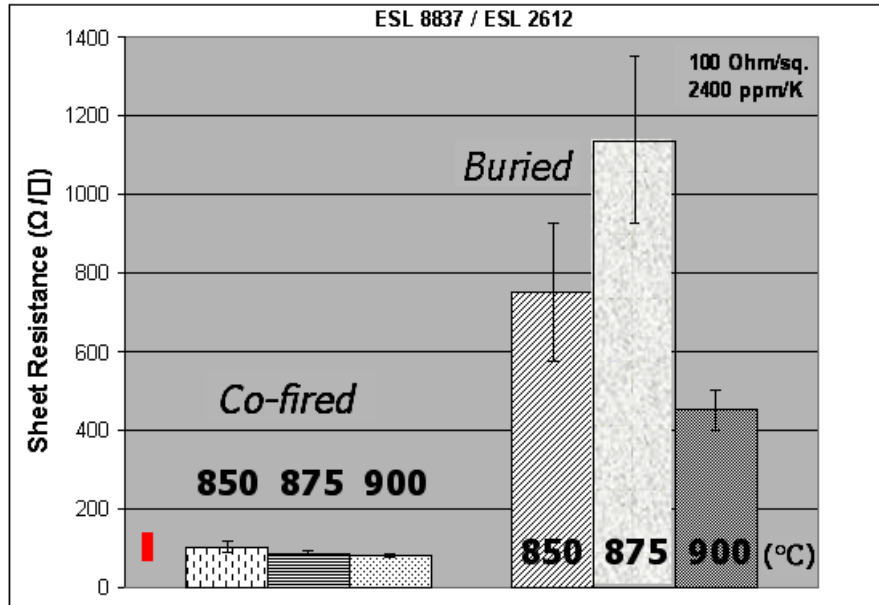


- **non-reproducible TCR values**
- standard deviation is very big

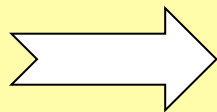


PROPERTIES

SHEET RESISTANCE

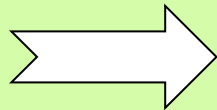


Co-fired
Samples



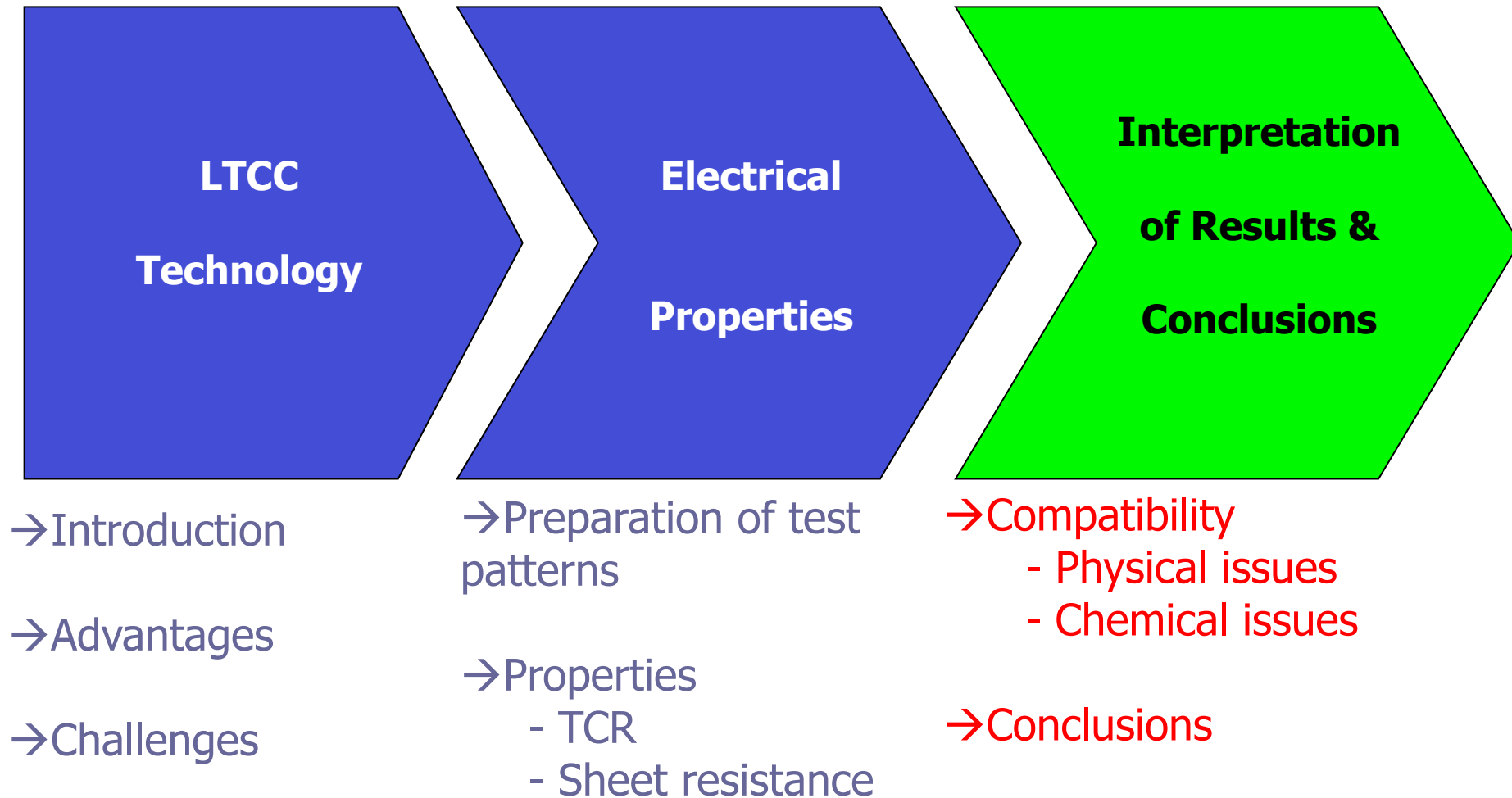
- close to producer-specified values
- standard deviation is small

Buried
Samples



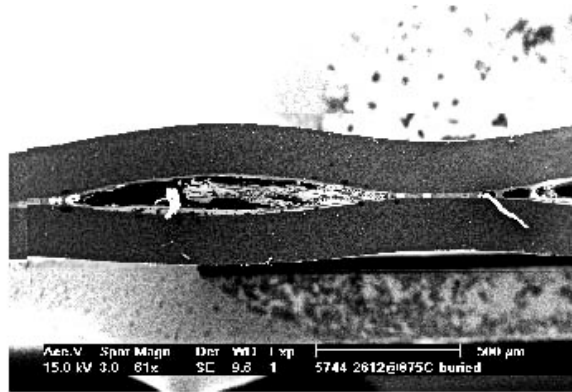
- **non-reproducible sheet resistance values** (particularly for ESL 8837)
- standard deviation is very big

OUTLINE OF THIS PRESENTATION

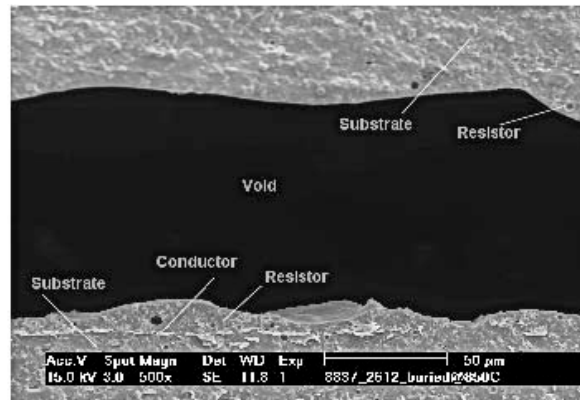


A. Physical Issues

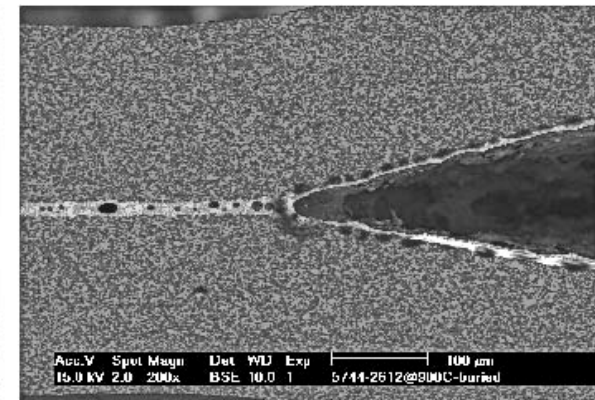
Buried structures fired at 850°C



Conductor – Resistor



Cavity due to entrapped gases



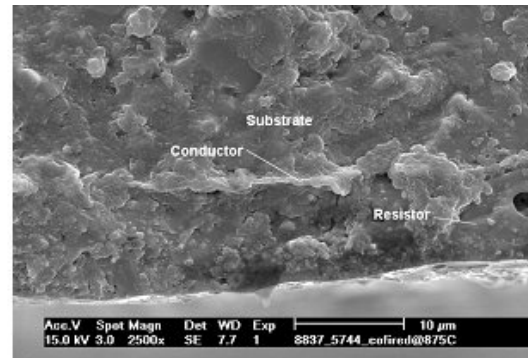
Conductor-Resistor

⇒ Deformation of the structure due to entrapped gases after burn-out of organics in the pastes *(at contacts)*.

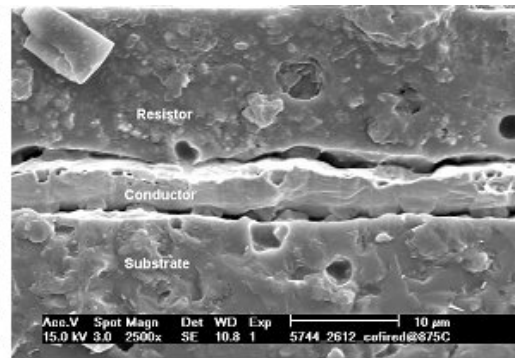
Delamination of component layers at contacts resulting in **termination problems** particularly for short resistors

COMPATIBILITY OF COMPONENTS

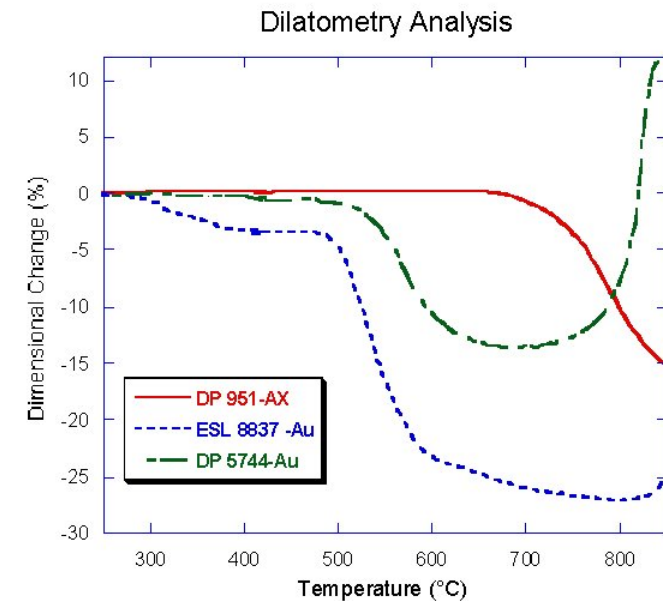
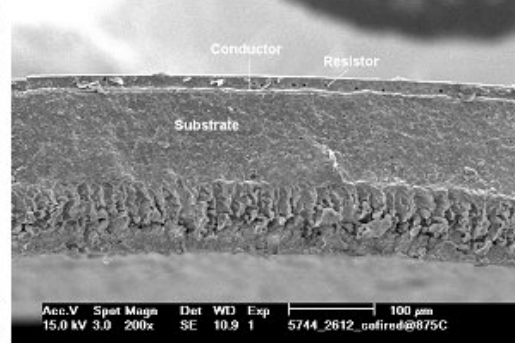
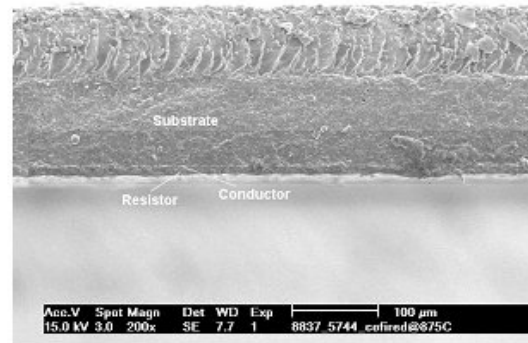
Co-fired structures using different conductor pastes at 850°C



ESL 8837



DP 5744

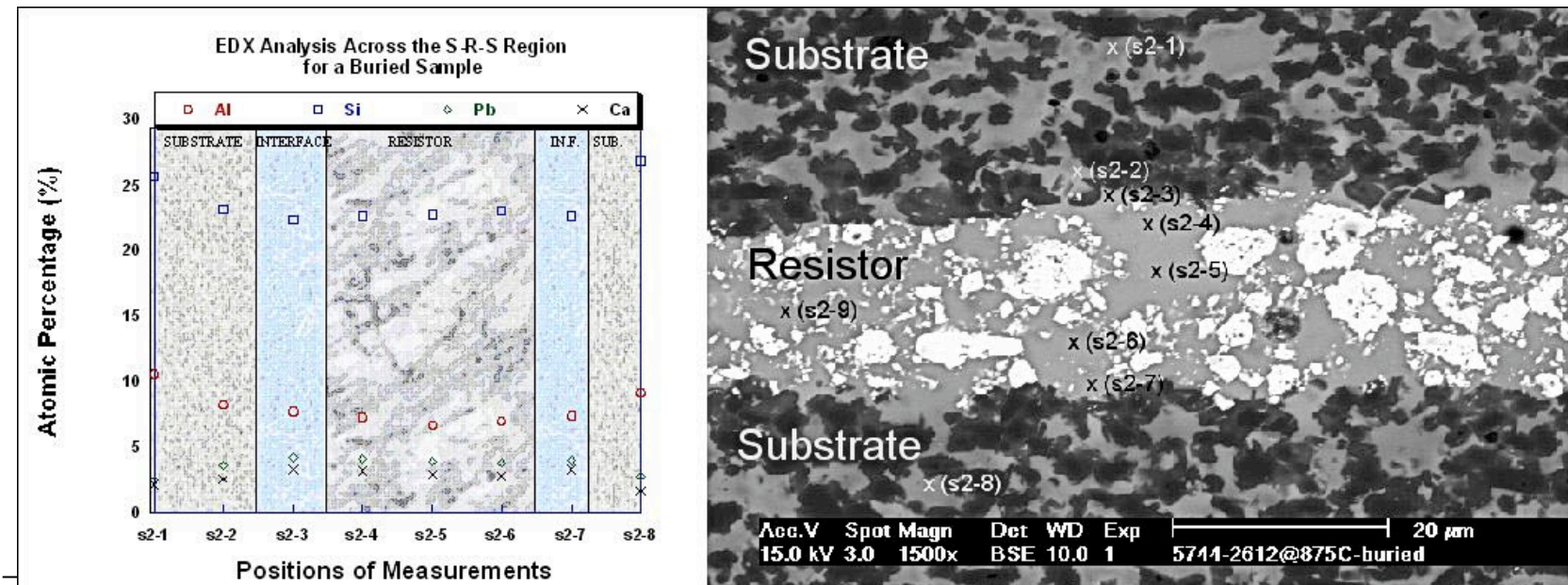


⇒ $t_{\text{fired}} (\text{DP 5744-Au}) > t_{\text{fired}} (\text{ESL 8837-Au})$
 ⇒ Expansion of DP 5744-Au conductor after 700°C

Increased deformation in
DP 5744-Au used-samples
during co-firing

B. Chemical Issues

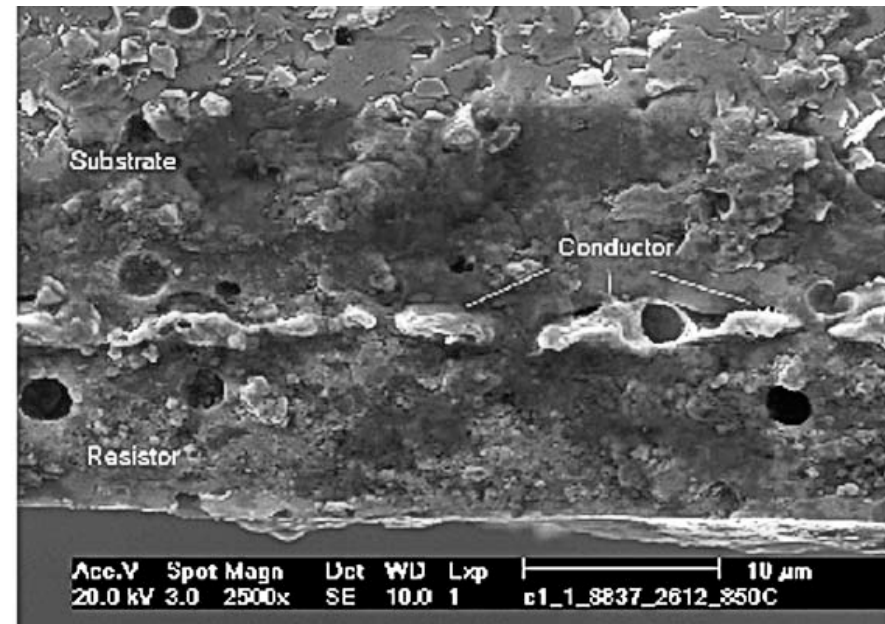
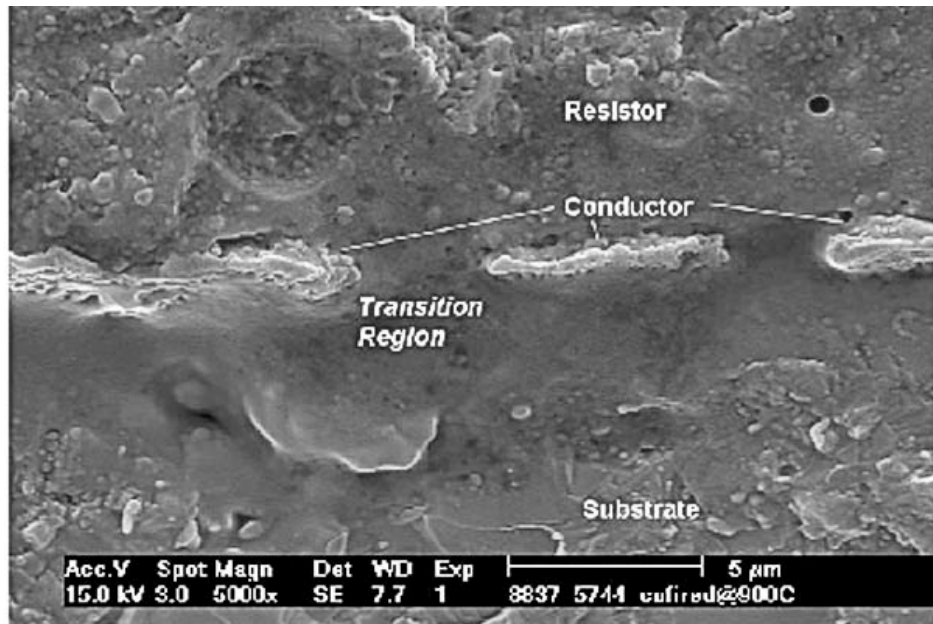
Chemical analysis by EDXS across the substrate-resistor-substrate region of a buried sample



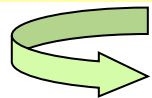
⇒ Concentration of certain elements show a distribution over the interfaces between components

Indicator for **formation of new phases**, which directly affects the properties

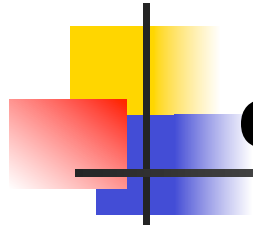
COMPATIBILITY OF COMPONENTS



⇒ Glass additive, which is mobile at T_G , is observed to migrate easily between components.

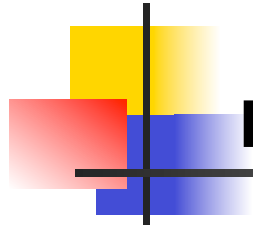


(Porosity within the components, fine thicknesses enhance this effect)



CONCLUSIONS

- ➔ Processing parameters are to be yet optimized for buried firing.
- ➔ Differential shrinkage, printed paste thickness, chemical interaction are pointed to be the main cause of unreliability.
- ➔ Selected pastes cannot be totally considered compatible.



NEXT STEPS

- ✗ Improving processing conditions
- ✗ Better understanding the nature of the components being used and their reactions to varying processing parameters
- ✗ Matching of the components' sintering behavior to that of the tape
- ✗ More analysis on the chemical interactions between the components